

<b>Notice of References Cited</b>		Application/Control No. 10/772,315	Applicant(s)/Patent Under Reexamination YOON ET AL.	
		Examiner MARIA VERONICA D. EWALD	Art Unit 1791	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,390,485	06-1983	Yang, Wen-Jei	264/449
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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